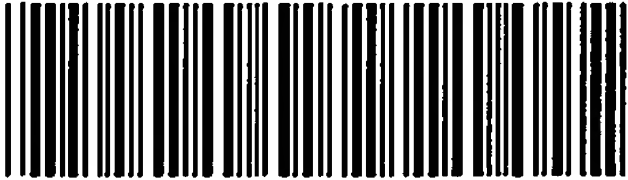


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/647,762	HAN ET AL.	
	Examiner	Art Unit	
	Paul D. Kim	3729	

SEARCHED			
Class	Subclass	Date	Examiner
29	592.1	8/30/2005	PK
	603.12-603.18		
	829		
	831		
	851		
	885		
360	121-126		
	317		
427	127		
	128		
451	5		
	41		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Text Search EAST/NPL (IEEE)	8/31/2005	PK